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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/527,396	RIEDEL ET AL.	
Examiner	Art Unit	
Patrick J. Lee	2878	

Patrick J. Lee

SEARCHED			
Class	Subclass	Date	Examiner
250	214R, 214C, 214DC, 214A	464p6 405106	PL
327	514		PL
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
Consulted w/ S. Allen AU 2878 CL 250	4/24/2006	PL	
East (see attached) - USPAT, US- PGPUB, EPO, JPO, DERWENT	4/24/2006	PL	
East (see attached) - USPAT, US- PGPUB, EPO, JPO, DERWENT	4/25/2006	PL	
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